

# Generowanie wieloprzebiegowych kontrolowanych testów losowych

Ireneusz Mrozek (Foreign) <sup>1</sup>,

Vyacheslav Yarmolik <sup>2</sup>,

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<sup>1</sup> Foreign (Faculty of Computer Science, Bialystok University of Technology, Bialystok, Poland)

<sup>2</sup> Belarusian State University of Informatics and Radioelectronics, Faculty of Computer Systems and Networks, Minsk

**Keywords:** Random test, controlled memory test, multiple controlled random tests.

**Abstract:** Controlled Random Tests and methods for their generation have been analyzed and investigated. The similarities of all known controlled random testing approaches are shown. The new method and algorithm for Multiple Controlled Random Tests have been proposed and analyzed.

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